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APPLICANT  
Shozo Nagano et al.

FILING DATE  
February 14, 2001

GROUP  
1742

## U.S. PATENT DOCUMENTS

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
<i>AE</i>	AA	5,312,790	05-1994	Sengupta et al.	522	127	
	AB	5,435,826	07-1995	Sakakibara et al.	75	232	
	AC	5,486,491	01-1996	Sengupta et al.	501	137	
<i>AE</i>	AD	6,478,902 B2	11-2002	Koenigsmann et al.	148	681	
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

## FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
<i>AE</i>	AL	11323539	11-1999	Japan				
<i>AE</i>	AM	0441408A2	08-1991	EPO				
	AN							
	AO							
	AP							

## OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

<i>AE</i>	AR		Yeon et al., "Electrical Characteristics of the MOD-derived SrBi <sub>2</sub> xTa <sub>2</sub> O <sub>9</sub> and SrBi <sub>2.4</sub> (TA,Nb) <sub>2</sub> O <sub>9</sub> Thin Films", Journal of Materials Science, 35(10), pgs. 2405-2411, May 15, 2000. Abstract only.
<i>AE</i>	AS		Yan et al., "Preparation on the [(Pb,Lu) (Zr,Ti)O <sub>3</sub> ] Ferroelectric Thin Films by Using the Sol-Gel Processing", Piezoelectrics and Acousto-optics, Volume 17, issue n 5, October 1995, pgs. 24-27.
	AT		

EXAMINER

*S. Ip*

DATE CONSIDERED

*5/19/03*

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.